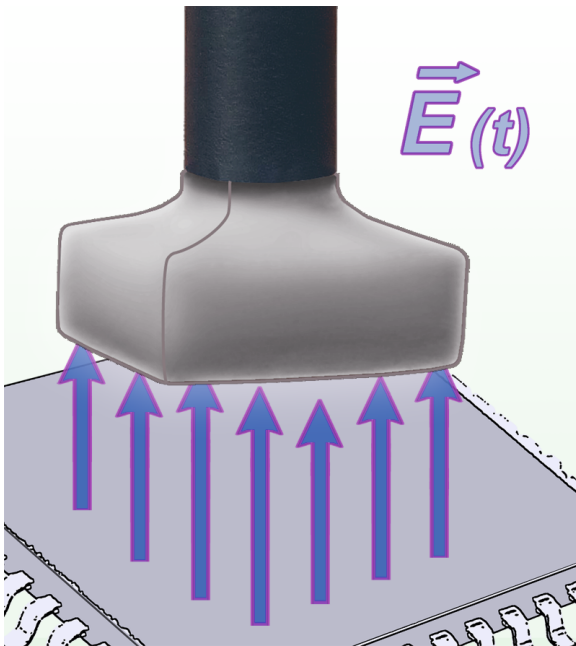


XFS-E 09s

Scanner Probe 30 MHz up to 6 GHz

LANGER
EMV-Technik



Short description

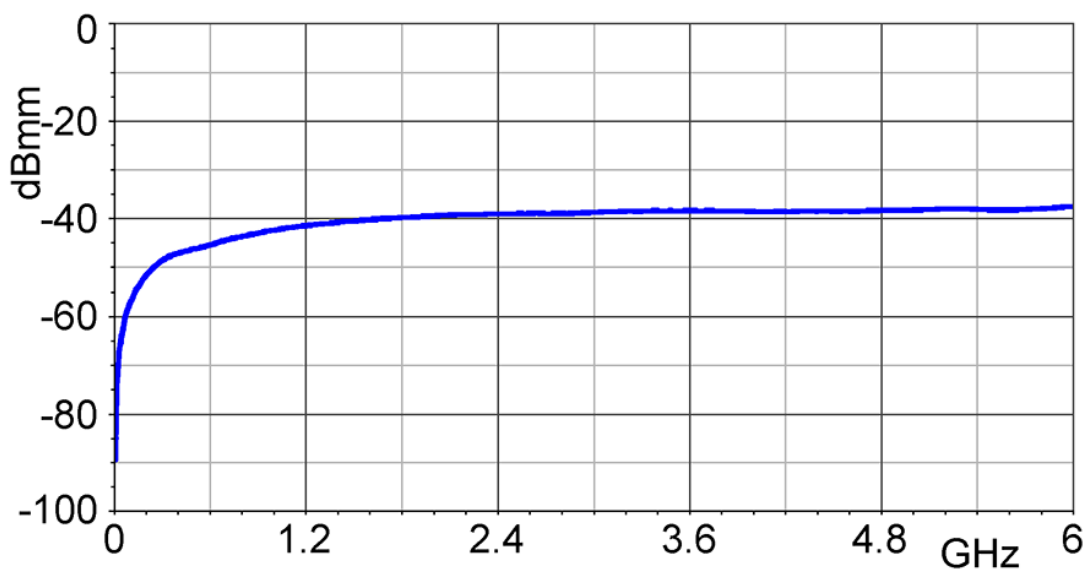
The electrode on the probe head of the XFS-E 09s scanner probe detects electrical fields which, for example are decoupled above the IC's surface. The probe's resolution allows for measurements with a distance of 0.5 mm to 10 mm above an assembly. For measurement, the E-field probe is placed on the target.

The XSF-E 09s is a passive near-field probe. To measure, the E-field probe is positioned above or onto components and printed circuit boards. It has a current attenuating sheath and, therefore, its upper half is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The E-field scanner probe has an internal terminating resistance.

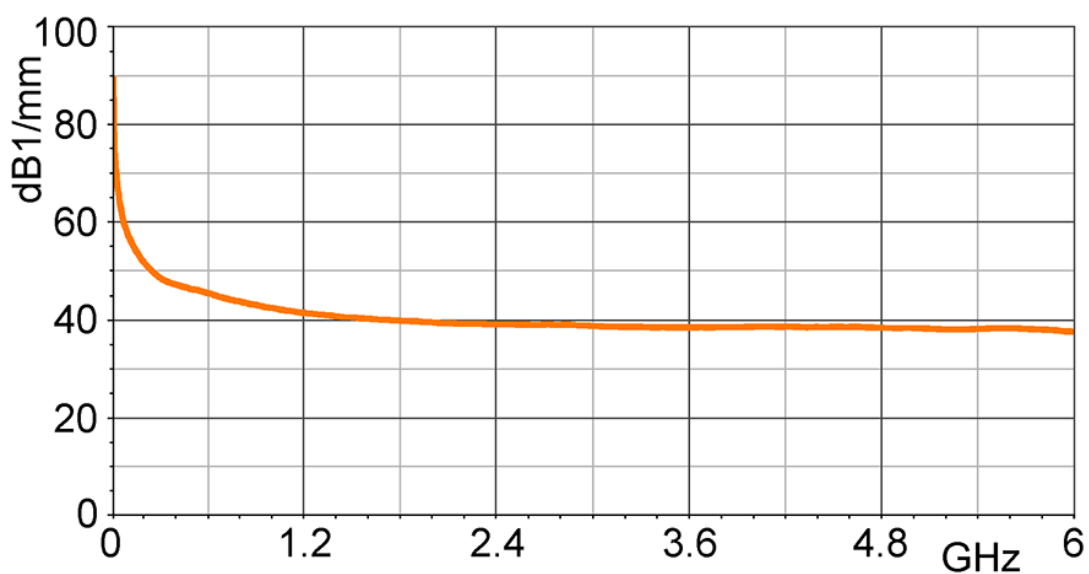
Technical parameters

Frequency range	30 MHz ... 6 GHz
Resolution	≈ 0.2 mm
Probe head dimensions:	$\approx (10 \times 10)$ mm
Connector - output	SMA, male, jack

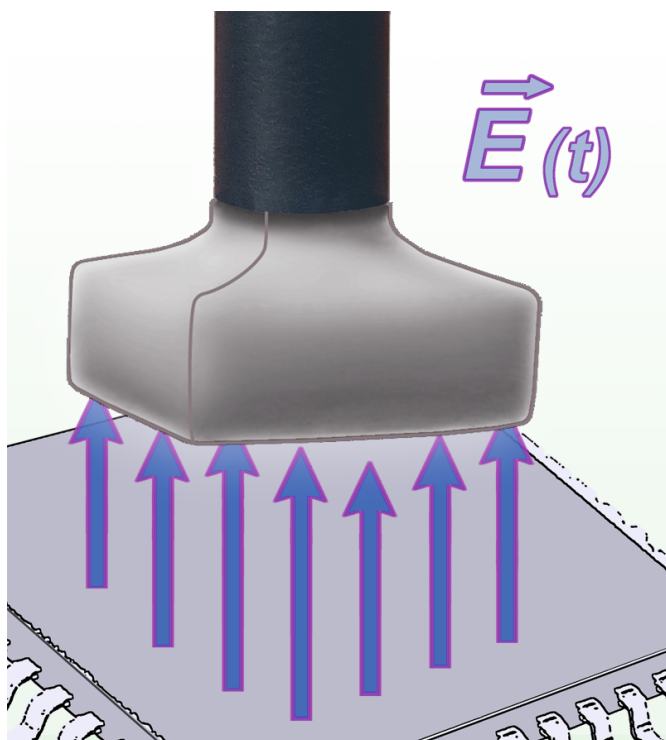
Frequency response [dB μ V] / [dB μ A/m]



E- field correction curve [dB μ V/mm] / [dB μ V]



Measuring principles



XFS-E 09s

Scanner Probe 30 MHz up to 6 GHz

LANGER
EMV-Technik

